

Search Notes**Application/Control No.**

10/565,394

Examiner

Hau V. Phan

Applicant(s)/Patent under Reexamination

KOBAYASHI ET AL.

Art Unit

3618

SEARCHED

Class	Subclass	Date	Examiner
180	89.2 309	2/19/2008	HP
	296		
	219		
181	250	2/19/2008	HP
	207		
	273		
	227		
60	322	2/19/2008	HP
	299		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR